

## EAST Search History

| Ref # | Hits | Search Query  | DBs   | Default Operator | Plurals | Time Stamp       |
|-------|------|---|---|------------------|---------|------------------|
| S1    | 7034 | chuck and wafer and plasma  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/11/28 14:10 |
| S2    | 920  | (arc or spike) and S1   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/06/11 17:45 |
| S3    | 775  | (etch or etching) and S2  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/06/11 17:54 |
| S4    | 170  | signal and detector and S3  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/06/11 17:53 |
| S5    | 640  | susceptor and (arc or spike) and semiconductor  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/06/11 17:54 |
| S6    | 412  | (etch or etching) and S5  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/06/11 17:54 |
| S7    | 17   | (dechucking or de-chucking) and S6  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/06/11 17:55 |
| S8    | 11   | ("20020043527"   "20020043530"   "20020055021"   "20030015521"   "4613455"   "5154863"   "5350720"   "6465763"   "6475606"   "6507006"   "6677557").PN. | US-PGPUB;<br>USPAT;<br>USOCR                                      | OR               | ON      | 2005/06/11 17:57 |

## EAST Search History

|     |       |   |   |    |    |                  |
|-----|-------|---|---|----|----|------------------|
| S9  | 2     | (arc adj detecting or arc adj detection) and (chuck or electro adj static adj chuck or esd adj chuck) | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 11:47 |
| S10 | 196   | rha.in.   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 12:20 |
| S11 | 25    | circuit and S10   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 12:21 |
| S12 | 0     | john adj rha  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 12:22 |
| S13 | 34930 | adams.in.   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 12:22 |
| S14 | 721   | wafer and S13   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 12:22 |
| S15 | 399   | circuit and S14   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 12:22 |
| S16 | 148   | (detect or detecting or detection) and S15  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 12:23 |

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|     |    |                                       |   |    |    |                  |
|-----|----|---------------------------------------|---|----|----|------------------|
| S17 | 26 | (arc or arcing) and S16               | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 12:23 |
| S18 | 12 | (etch or etching) and S17             | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 12:23 |
| S19 | 60 | vrf near4 circuit                     | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 12:26 |
| S20 | 3  | gate adj input and S19                | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 12:38 |
| S21 | 0  | esc same vrf and signal and circuit   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 12:38 |
| S22 | 0  | (esc same vrf) and signal and circuit | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 12:38 |
| S23 | 2  | esc and vrf and signal and circuit    | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 12:59 |
| S24 | 5  | comdel.as.                            | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 13:01 |

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|     |     |  |   |    |    |                  |
|-----|-----|--|---|----|----|------------------|
| S25 | 26  | "5175472".uref.  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 13:05 |
| S26 | 1   | arcng adj suppression adj circuit<br>or arching adj suppress adj circuit | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 13:07 |
| S27 | 27  | spike adj suppression adj circuit or<br>spike adj suppress adj circuit   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 13:07 |
| S28 | 0   | data adj aquisition and wafer and<br>etch and spike                      | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 13:18 |
| S29 | 669 | over adj voltage adj protection adj<br>circuit                           | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 13:35 |
| S30 | 5   | a/d and d/a and S29  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/06/22 13:36 |
| S31 | 207 | rha.in.  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:11 |
| S32 | 535 | farjami  | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:11 |

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|     |         |                       |   |    |    |                  |
|-----|---------|-----------------------|---|----|----|------------------|
| S33 | 0       | S31 and S32           | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:11 |
| S34 | 575532  | etch or etching       | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:11 |
| S35 | 0       | S33 and S34           | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:11 |
| S36 | 2325947 | wafer or substrate    | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:11 |
| S37 | 233     | S32 and S36           | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:16 |
| S38 | 598496  | arc or arcing         | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:17 |
| S39 | 36      | S37 and S38           | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:18 |
| S40 | 113906  | detection adj circuit | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:19 |

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|     |        |   |   |    |    |                  |
|-----|--------|---|---|----|----|------------------|
| S41 | 1      | chucking adj spike                                    | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:20 |
| S42 | 100402 | spike or spiking                                      | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:20 |
| S43 | 88     | electro-static adj chuck or<br>electostatic adj chuck | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:20 |
| S44 | 0      | S42 and S43   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:21 |
| S45 | 10300  | esc   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:21 |
| S46 | 175    | S42 and S45   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:21 |
| S47 | 70     | S34 and S46   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:21 |
| S48 | 719451 | failure   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON | 2005/11/28 14:21 |

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|     |     |   |   |    |     |                  |
|-----|-----|---|---|----|-----|------------------|
| S49 | 30  | S47 and S48   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON  | 2005/11/28 14:21 |
| S50 | 406 | (438/5).CCLS.   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/03/11 13:10 |
| S51 | 0   | (magnitude and chuck and wafer and arc and detect and spike).clm. | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON  | 2006/03/11 13:12 |
| S52 | 0   | (chuck and wafer and arc and detect and spike).clm.               | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON  | 2006/03/11 13:12 |
| S53 | 0   | (chuck and current and arc and detect and spike).clm.             | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON  | 2006/03/11 13:12 |
| S54 | 0   | (chuck and current and arc and detect and spiked).clm.            | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON  | 2006/03/11 13:12 |
| S55 | 1   | (chuck and current and arc and detect).clm.                       | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | ON  | 2006/03/11 13:14 |
| S56 | 0   | (250/791.5).CCLS.   | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/03/11 13:14 |

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|     |    |                   |   |    |     |                  |
|-----|----|-------------------|---|----|-----|------------------|
| S57 | 62 | (205/791.5).CCLS. | US-PGPUB;<br>USPAT;<br>USOCR;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR | OFF | 2006/03/11 13:14 |
|-----|----|-------------------|---|----|-----|------------------|